BLF8G27LS-150V; **BLF8G27LS-150GV**

Power LDMOS transistor

Rev. 3 — 26 June 2013

Product data sheet

1. Product profile

1.1 General description

150W LDMOS power transistor with improved video bandwidth for base station applications at frequencies from 2500 MHz to 2700 MHz.

Table 1. Typical performance

Typical RF performance at T_{case} = 25 °C in a common source class-AB production test circuit.

| Test signal | f | I _{Dq} | V _{DS} | P _{L(AV)} | Gp | η_{D} | ACPR _{5M} |
|------------------|--------------|-----------------|-----------------|--------------------|------|-------------------|--------------------|
| | (MHz) | (mA) | (V) | (W) | (dB) | (%) | (dBc) |
| 2-carrier W-CDMA | 2600 to 2700 | 1300 | 28 | 45 | 18 | 30 | -30 ^[1] |

^{[1] 3}GPP test model 1; 64 DPCH; PAR = 8.4 dB at 0.01 % probability on CCDF; carrier spacing 5 MHz. Channel bandwidth is 3.84 MHz.

1.2 Features and benefits

- Excellent ruggedness
- High efficiency
- Low R_{th} providing excellent thermal stability
- Decoupling leads to enable improved video bandwidth (60 MHz typical)
- Lower output capacitance for improved performance in Doherty applications
- Designed for low memory effects providing excellent digital pre-distortion capability
- Internally matched for ease of use
- Integrated ESD protection
- Design optimized for gull-wing
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)

1.3 Applications

RF power amplifiers for W-CDMA base stations and multi carrier applications in the 2500 MHz to 2700 MHz frequency range



2. Pinning information

Table 2. Pinning

| Pin | Description | Simplified outline | Graphic symbol |
|---------|----------------------|--------------------|-----------------------------|
| BLF8G27 | 7LS-150V (SOT1244B) | • | |
| 1 | drain | | |
| 2 | gate | — 4 1 5 ∏ | 6 7 → 1 → 4,5 |
| 3 | source <u>[</u> | | 6,7 |
| 4 | decoupling lead | 3 | 2 — — 3 |
| 5 | decoupling lead | | aaa-003619 |
| 6 | n.c. | | |
| 7 | n.c. | 6 2 7 | |
| BLF8G27 | 7LS-150GV (SOT1244C) | | |
| 1 | drain | | , |
| 2 | gate | - 4 1 5 | 6 7 - 1 - 4.5 |
| 3 | source [| | 6,7 |
| 4 | decoupling lead | | 2 — — 3 |
| 5 | decoupling lead | | aaa-003619 |
| 6 | n.c. | 6 2 7 3 | |
| 7 | n.c. | | |

^[1] Connected to flange.

3. Ordering information

Table 3. Ordering information

| Type number | Packa | Package | | | |
|-----------------|-------|--|----------|--|--|
| | Name | Description | Version | | |
| BLF8G27LS-150V | - | earless flanged ceramic package; 6 leads | SOT1244B | | |
| BLF8G27LS-150GV | - | earless flanged ceramic package; 6 leads | SOT1244C | | |

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol | Parameter | Conditions | Min | Max | Unit |
|------------------|----------------------|------------|-------|------|------|
| V_{DS} | drain-source voltage | | - | 65 | V |
| V_{GS} | gate-source voltage | | -0.5 | +13 | V |
| T _{stg} | storage temperature | | -65 | +150 | °C |
| Tj | junction temperature | | [1] _ | 225 | °C |

^[1] Continuous use at maximum temperature will affect the reliability.

5. Thermal characteristics

Table 5. Thermal characteristics

| Symbol | Parameter | Conditions | Тур | Unit |
|---------------|--|----------------------------------|------|------|
| $R_{th(j-c)}$ | thermal resistance from junction to case | T_{case} = 80 °C; P_L = 45 W | 0.30 | K/W |

6. Characteristics

Table 6. DC characteristics

 $T_i = 25$ °C unless otherwise specified.

| ., | | | | | | |
|---------------------|----------------------------------|--|-----|------|-----|------|
| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
| $V_{(BR)DSS}$ | drain-source breakdown voltage | $V_{GS} = 0 \text{ V}; I_D = 2.16 \text{ mA}$ | 65 | - | - | V |
| $V_{GS(th)}$ | gate-source threshold voltage | $V_{DS} = 10 \text{ V}; I_D = 216 \text{ mA}$ | 1.5 | 1.9 | 2.3 | V |
| I _{DSS} | drain leakage current | $V_{GS} = 0 \text{ V}; V_{DS} = 28 \text{ V}$ | - | - | 4.5 | μΑ |
| I _{DSX} | drain cut-off current | $V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $V_{DS} = 10 \text{ V}$ | - | 40 | - | Α |
| I _{GSS} | gate leakage current | $V_{GS} = 11 \text{ V}; V_{DS} = 0 \text{ V}$ | - | - | 450 | nΑ |
| 9 _{fs} | forward transconductance | $V_{DS} = 10 \text{ V}; I_{D} = 10.8 \text{ A}$ | - | 16 | - | S |
| R _{DS(on)} | drain-source on-state resistance | $V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $I_D = 7.56 \text{ A}$ | - | 0.06 | - | Ω |
| | | | | | | |

Table 7. RF characteristics

Test signal: 2-carrier W-CDMA, 3GPP test model; 64 DPCH; PAR = 8.4 dB at 0.01 % probability on the CCDF, carrier spacing 5 MHz; f_1 = 2602.5 MHz; f_2 = 2607.5 MHz; f_3 = 2692.5 MHz; f_4 = 2697.5 MHz; RF performance at V_{DS} = 28 V; I_{Dq} = 1300 mA; T_{case} = 25 °C; unless otherwise specified; in a class-AB production test circuit.

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|--------------------|--------------------------------------|----------------------------|------|-----|-----|------|
| Gp | power gain | $P_{L(AV)} = 45 \text{ W}$ | 16.8 | 18 | - | dB |
| RLin | input return loss | $P_{L(AV)} = 45 \text{ W}$ | - | -10 | -7 | dB |
| η_{D} | drain efficiency | $P_{L(AV)} = 45 \text{ W}$ | 26 | 30 | - | % |
| ACPR _{5M} | adjacent channel power ratio (5 MHz) | $P_{L(AV)} = 45 \text{ W}$ | - | -30 | -26 | dBc |

7. Test information

7.1 Ruggedness in class-AB operation

The BLF8G27LS-150V and BLF8G27LS-150GV are capable of withstanding a load mismatch corresponding to VSWR = 10 : 1 through all phases under the following conditions: $V_{DS} = 28 \text{ V}$; $I_{Dq} = 1300 \text{ mA}$; $P_L = 150 \text{ W}$ (CW); f = 2600 MHz.

7.2 Impedance information

Table 8. Typical impedance

Measured load-pull data; $I_{Da} = 1300 \text{ mA}$; $V_{DS} = 28 \text{ V}$.

| f | Z _S ^[1] | Z _L [1] |
|-----------------|-------------------------------|---------------------|
| (MHz) | (Ω) | (Ω) |
| BLF8G27LS-150V | | |
| 2500 | 0.70 – j3.50 | 2.68 – j1.86 |
| 2600 | 1.10 – j4.40 | 2.86 – j2.03 |
| 2700 | 2.00 – j4.90 | 3.27 – j1.87 |
| BLF8G27LS-150GV | | |
| 2500 | 1.00 – j5.70 | 2.35 – j4.04 |
| 2600 | 1.50 – j6.90 | 2.52 – j4.32 |
| 2700 | 2.10 – j8.00 | 3.21 – j4.36 |

[1] Z_S and Z_L defined in Figure 1.

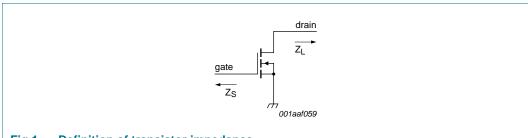


Fig 1. Definition of transistor impedance

7.3 Test circuit

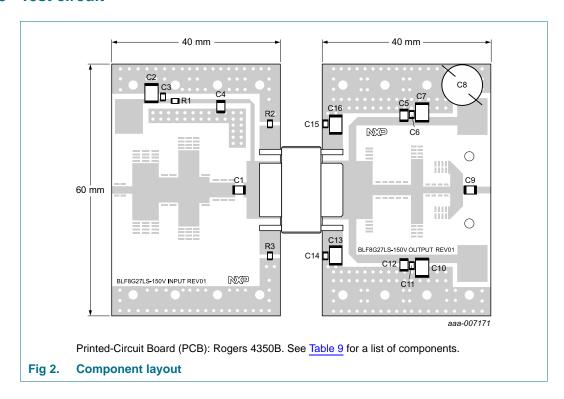


Table 9. List of components

See Figure 2 for component layout.

The used PCB material is Rogers RO4350B with a thickness of 0.76 mm.

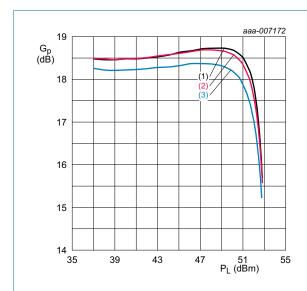
| Component | Description | Value | Remarks |
|-------------------|-----------------------------------|-------------------------------|-------------|
| C1 | multilayer ceramic chip capacitor | 0.7 μF | [1] ATC800B |
| C2 | multilayer ceramic chip capacitor | 1 μF | [2] Murata |
| C3 | multilayer ceramic chip capacitor | 100 nF | [2] Murata |
| C4, C5, C9, C12 | multilayer ceramic chip capacitor | 24 pF | [1] ATC800B |
| C6, C11, C14, C15 | multilayer ceramic chip capacitor | 220 nF | [2] Murata |
| C7, C10, C13, C16 | multilayer ceramic chip capacitor | $4.7~\mu\text{F},50~\text{V}$ | [2] Murata |
| C8 | electrolytic capacitor | $>$ 470 μ F, 63 V | |
| R1 | chip resistor | 4.7 Ω , 1 % tolerance | SMD 1206 |
| R2, R3 | chip resistor | 0 Ω | SMD 1206 |

^[1] American Technical Ceramics type 800B or capacitor of same quality.

^[2] Murata or capacitor of same quality.

7.4 Graphical data

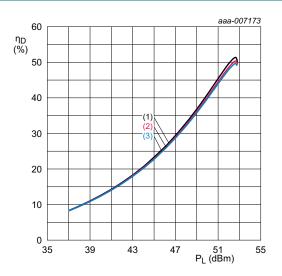
7.4.1 Pulsed CW



 V_{DS} = 28 V; I_{Dq} = 1300 mA; t_p = 100 $\mu s; \, \delta$ = 10 %.

- (1) f = 2600 MHz
- (2) f = 2655 MHz
- (3) f = 2700 MHz

Fig 3. Power gain as a function of output power; typical values

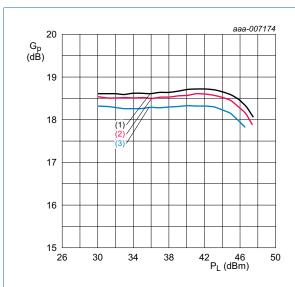


 V_{DS} = 28 V; I_{Dq} = 1300 mA; t_p = 100 $\mu s;$ δ = 10 %.

- (1) f = 2600 MHz
- (2) f = 2655 MHz
- (3) f = 2700 MHz

Fig 4. Drain efficiency as a function of out power; typical values

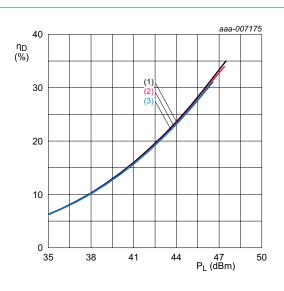
7.4.2 IS-95



 $V_{DS} = 28 \text{ V}; I_{Dq} = 1300 \text{ mA}.$

- (1) f = 2605 MHz
- (2) f = 2655 MHz
- (3) f = 2695 MHz

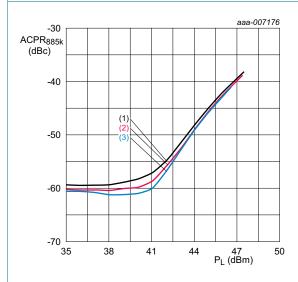
Fig 5. Power gain as a function of output power; typical values



 $V_{DS} = 28 \text{ V}; I_{Dq} = 1300 \text{ mA}.$

- (1) f = 2605 MHz
- (2) f = 2655 MHz
- (3) f = 2695 MHz

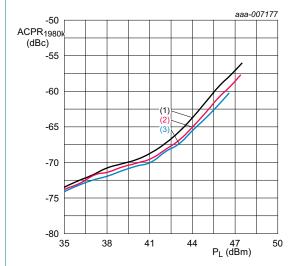
Fig 6. Drain efficiency as a function of output power; typical values



 $V_{DS} = 28 \text{ V}; I_{Dq} = 1300 \text{ mA}.$

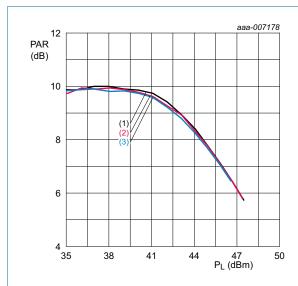
- (1) f = 2605 MHz
- (2) f = 2655 MHz
- (3) f = 2695 MHz

Fig 7. Adjacent channel power ratio (885 kHz) as a function of output power; typical values



- (1) f = 2605 MHz
- (2) f = 2655 MHz
- (3) f = 2695 MHz

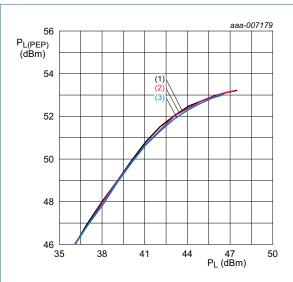
Fig 8. Adjacent channel power ratio (1980 kHz) as a function of output power; typical values



 $V_{DS} = 28 \text{ V}; I_{Dq} = 1300 \text{ mA}.$

- (1) f = 2605 MHz
- (2) f = 2655 MHz
- (3) f = 2695 MHz

Fig 9. Peak-to-average power ratio as a function of output power; typical values

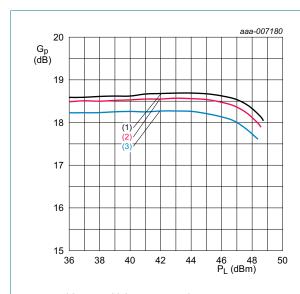


 $V_{DS} = 28 \text{ V}; I_{Dq} = 1300 \text{ mA}.$

- (1) f = 2605 MHz
- (2) f = 2655 MHz
- (3) f = 2695 MHz

Fig 10. Peak envelope power load power as a function of output power; typical values

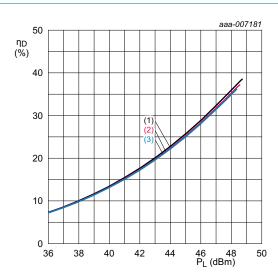
7.4.3 1-Carrier W-CDMA



 $V_{DS} = 28 \text{ V}; I_{Dq} = 1300 \text{ mA}.$

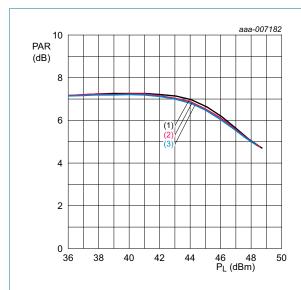
- (1) f = 2602.5 MHz
- (2) f = 2655 MHz
- (3) f = 2697.5 MHz

Fig 11. Power gain as a function of output power; typical values



- (1) f = 2602.5 MHz
- (2) f = 2655 MHz
- (3) f = 2697.5 MHz

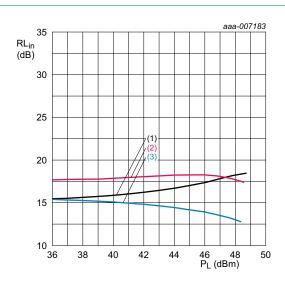
Fig 12. Drain efficiency as a function of output power; typical values



 $V_{DS} = 28 \text{ V}; I_{Dq} = 1300 \text{ mA}.$

- (1) f = 2602.5 MHz
- (2) f = 2655 MHz
- (3) f = 2697.5 MHz

Fig 13. Peak-to-average power ratio as a function of output power; typical values

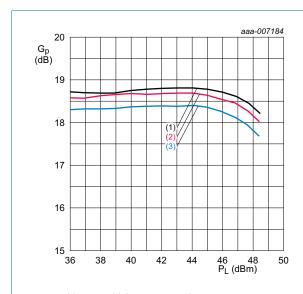


 $V_{DS} = 28 \text{ V}; I_{Dq} = 1300 \text{ mA}.$

- (1) f = 2602.5 MHz
- (2) f = 2655 MHz
- (3) f = 2697.5 MHz

Fig 14. Input return loss as a function of output power; typical values

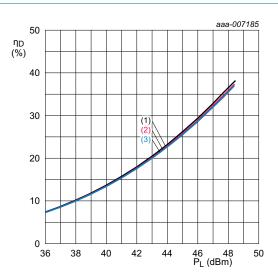
7.4.4 2-Carrier W-CDMA



 $V_{DS} = 28 \text{ V}; I_{Dq} = 1300 \text{ mA}.$

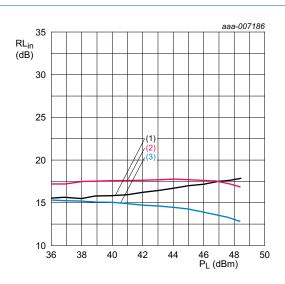
- (1) f = 2605 MHz
- (2) f = 2655 MHz
- (3) f = 2695 MHz

Fig 15. Power gain as a function of output power; typical values



- (1) f = 2605 MHz
- (2) f = 2655 MHz
- (3) f = 2695 MHz

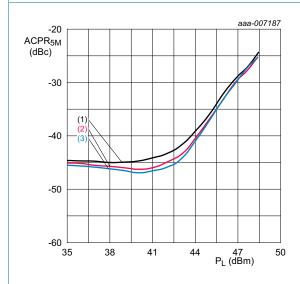
Fig 16. Drain efficiency as a function of output power; typical values



 $V_{DS} = 28 \text{ V}; I_{Dq} = 1300 \text{ mA}.$

- (1) f = 2605 MHz
- (2) f = 2655 MHz
- (3) f = 2695 MHz

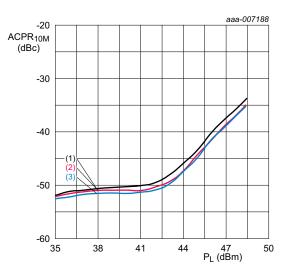
Fig 17. Input return loss as a function of output power; typical values



 $V_{DS} = 28 \text{ V}; I_{Dq} = 1300 \text{ mA}.$

- (1) f = 2605 MHz
- (2) f = 2655 MHz
- (3) f = 2695 MHz

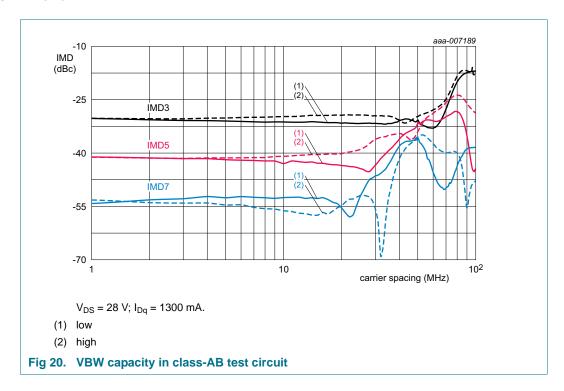
Fig 18. Adjacent channel power ratio (5 MHz) as a function of output power; typical values



- (1) f = 2605 MHz
- (2) f = 2655 MHz
- (3) f = 2695 MHz

Fig 19. Adjacent channel power ratio (10 MHz) as a function of output power; typical values

7.4.5 2-Tone VBW



8. Package outline

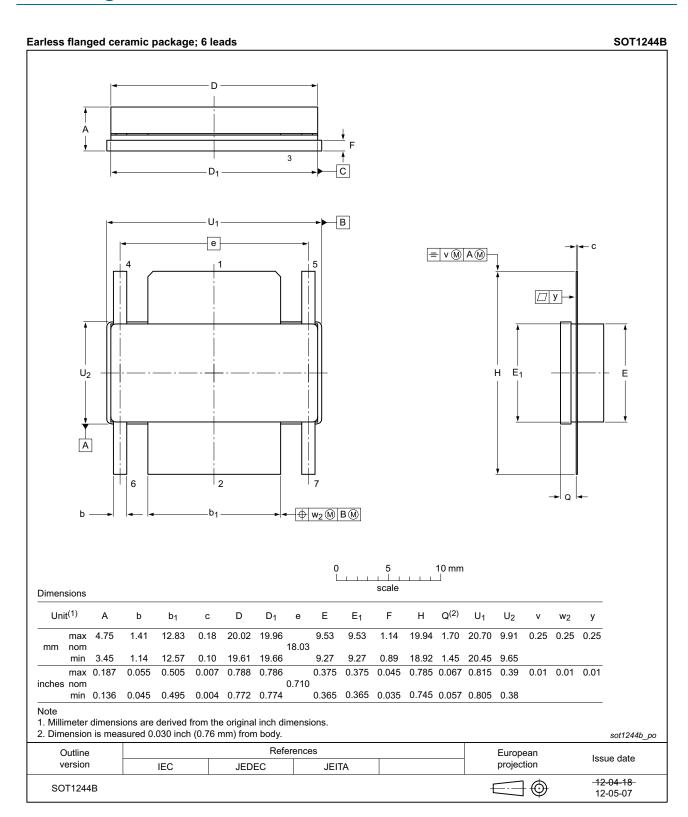


Fig 21. Package outline SOT1244B

BLF8G27LS-150V_8G27LS-150GV

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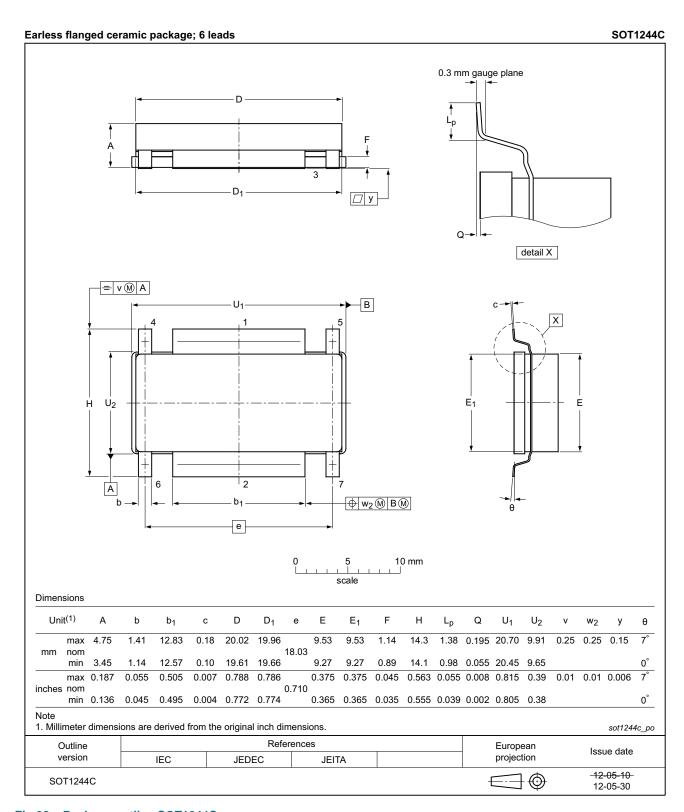


Fig 22. Package outline SOT1244C

9. Handling information

CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Observe precautions for handling electrostatic sensitive devices.

Such precautions are described in the ANSI/ESD S20.20, IEC/ST 61340-5, JESD625-A or equivalent standards.

10. Abbreviations

Table 10. Abbreviations

| Acronym | Description |
|---------|--|
| 3GPP | 3rd Generation Partnership Project |
| CCDF | Complementary Cumulative Distribution Function |
| CW | Continuous Wave |
| DPCH | Dedicated Physical CHannel |
| ESD | ElectroStatic Discharge |
| IS-95 | Interim Standard 95 |
| LDMOS | Laterally Diffused Metal Oxide Semiconductor |
| PAR | Peak-to-Average Ratio |
| SMD | Surface Mounted Device |
| VBW | Video BandWidth |
| VSWR | Voltage Standing Wave Ratio |
| W-CDMA | Wideband Code Division Multiple Access |
| | |

11. Revision history

Table 11. Revision history

| Document ID | Release date | Data sheet status | Change notice | Supersedes | |
|---------------------------------|--|------------------------|---------------|-------------------------------------|--|
| BLF8G27LS-150V_8G27LS-150GV v.3 | 20130626 | Product data sheet | - | BLF8G27LS-150V_ 8G27LS-150GV v.2 | |
| Modifications: | <u>Table 2 on page 2</u>: table has been updated | | | | |
| | • Table 5 on | page 3: table has been | updated | | |
| | • Table 6 on | page 3: table has been | updated | | |
| | • Table 7 on | page 3: table has been | updated | | |
| BLF8G27LS-150V_8G27LS-150GV v.2 | 20130422 | Objective data sheet | - | BLF8G27LS-150V_ | |
| | | | | 8G27LS-150GV v.1 | |
| BLF8G27LS-150V_8G27LS-150GV v.1 | 20130129 | Objective data sheet | - | - | |

12. Legal information

12.1 Data sheet status

| Document status[1][2] | Product status[3] | Definition |
|--------------------------------|-------------------|---|
| Objective [short] data sheet | Development | This document contains data from the objective specification for product development. |
| Preliminary [short] data sheet | Qualification | This document contains data from the preliminary specification. |
| Product [short] data sheet | Production | This document contains the product specification. |

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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BLF8G27LS-150(G)V

Power LDMOS transistor

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BLF8G27LS-150(G)V

Power LDMOS transistor

14. Contents

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